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PATENT  
81790.0189

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

MOMOHARA, Tomomi

Serial No: 09/686,200 (reissue of 08/718,660)

Filed: October 5, 2000

For: PROBE CARD HAVING GROUPS  
OF PROBE NEEDLES IN A  
PROBING TEST APPARATUS FOR  
TESTING SEMICONDUCTOR  
INTEGRATED CIRCUITS

Art Unit: 2829

Examiner: NGUYEN, Vinh P.

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:	
Commissioner for Patents Washington D.C. 20231, on	
April 10, 2003	
Date of Deposit	
Michael Crapenchoff, Reg. No. 37,115	
Name	April 10, 2003
Signature	Date

AMENDMENT

Commissioner for Patents  
Washington, D.C. 20231

Dear Sir:

In response to the Office Action dated October 10, 2002, the time for response to which is extended three months by the accompanying petition from January 10, 2003 to April 10, 2003, please amend the above-referenced reissue application as follows:

IN THE CLAIMS:

Please replace the text of claims 6-11 with the following amended text:

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APR 10 2003

TECHNOLOGY CENTER 2800

6. (Amended) A method for testing semiconductor integrated circuits, the method comprising:

providing a semiconductor wafer having a plurality of semiconductor integrated circuit chips arranged thereon in two columns and at least two rows, each of said plurality of semiconductor integrated chips having a plurality of external terminals;